

## Bi-Polar HiPIMS deposited Nb<sub>3</sub>Sn

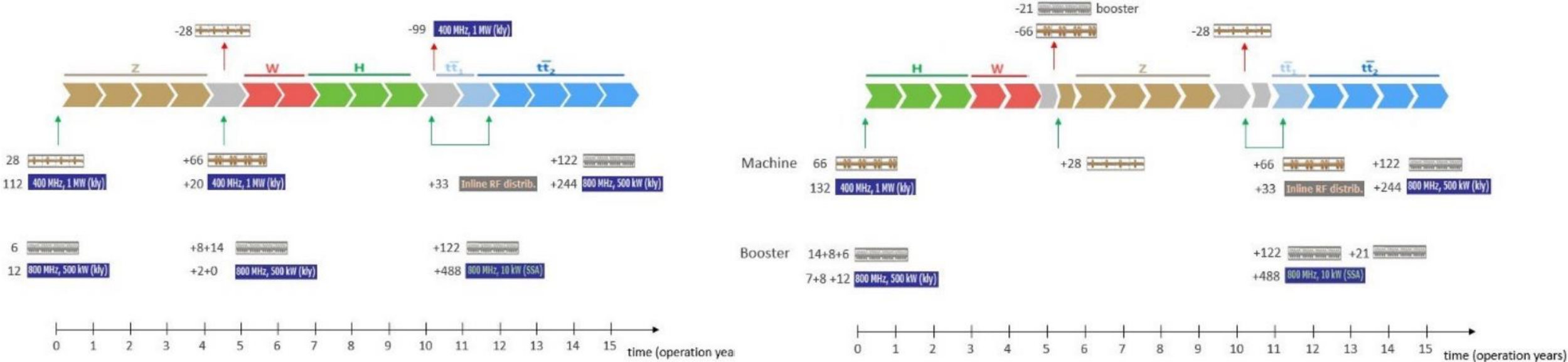
*What we know so far – a practical overview*

**S. Leith**, V. Giglia, G. Rosaz, C. P. A. Carlos, S. Pfeiffer, A. Moros, A.-T. Perez-Fontenla, L. Vega-Cid, K. Brunner, W. Venturini-Delsolaro, J. Bernardi, A. Steiger-Thirsfeld, J. Gruber, M. Himmerlich, V. Petit

# Outline

1. Context
2. European overview
3. Experimental setup
4. Feasibility
5. Target Management
6. Some process parameters' effects
7. Macroscopic defects library
8. QPR samples

# Context



FCC needs 100's of bulk Nb cavities for booster operation

Currently foreseen to operate at 2K

Could it be operated at 4.5K? Could we switch to Cu substrates?

**Nb<sub>3</sub>Sn / Cu appears as the most promising alternative**

# European overview - Actors

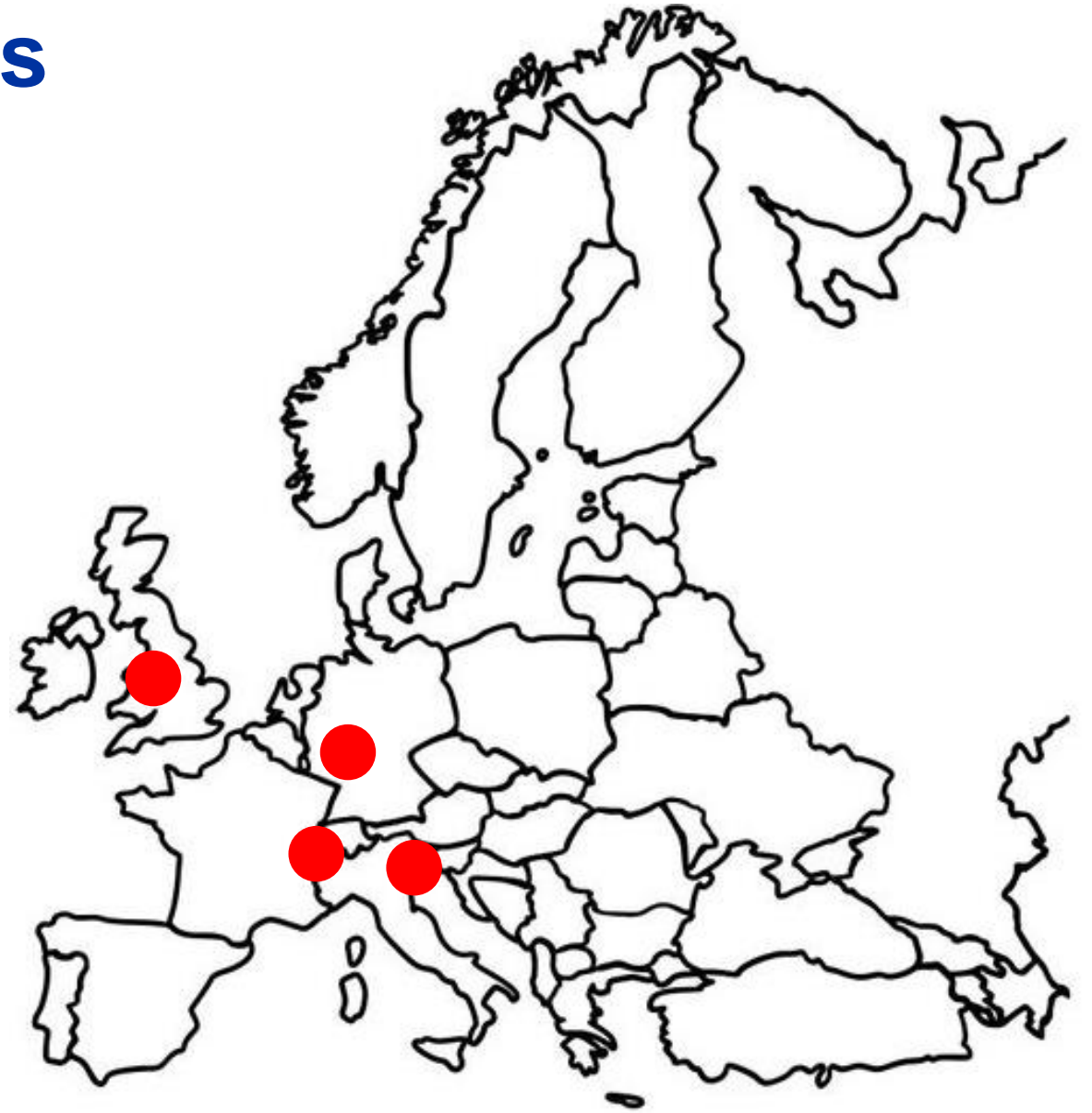
A15/Cu

STFC Daresbury Laboratory

TU Darmstadt

INFN Legnaro

CERN Geneva



# European overview - Techniques

## STFC Daresbury Laboratory

HiPIMS

## TU Darmstadt

Dual cathode DCMS

## INFN Legnaro

DCMS, dipped target

## CERN Geneva

Bipolar HiPIMS

## STFC Daresbury Laboratory

Samples / QPR

## TU Darmstadt

Samples

## INFN Legnaro

Samples, QPRs ... soon cavities

## CERN Geneva

Samples, QPRs, RADES, Magnetic flux lens discs

# Experimental Setup

Our point of view:

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**Our point of view: HiPIMS is a MUST** (as discussed yesterday)

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However:

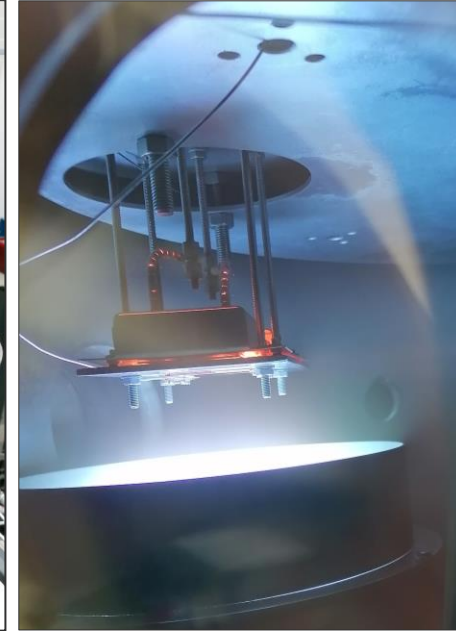
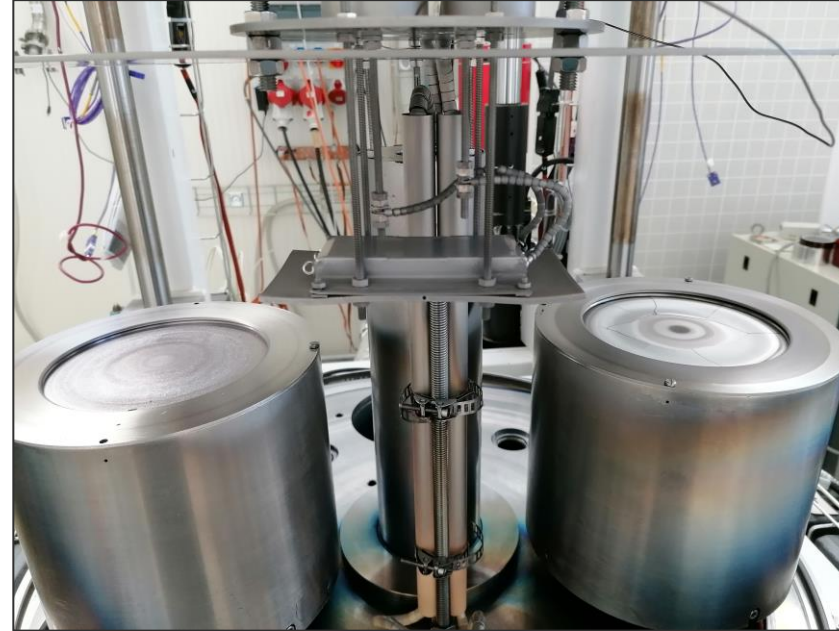
- Nb<sub>3</sub>Sn forms at rather low energy level (~750°C) vs HiPIMS bias (10's eV)
- Biasing is prompt to damage the lattice (see yesterday talk)
- Bias is needed for smoothness, density control
- Heat treatment is required to form proper A15 phase AND to recover defects



# Experimental Setup

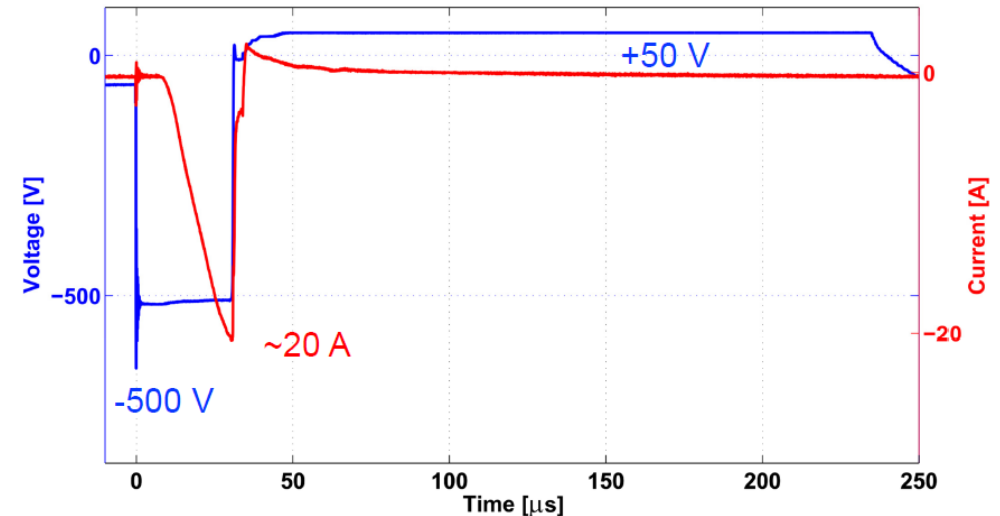
## Bi-Polar HiPIMS (Energy Pulse Systems)

- Two magnetrons 150mm diameter
- Working distance (100mm)
- Base pressure  $\sim 10^{-10}$  mbar after BO
- Target: alloyed Nb<sub>3</sub>Sn
- Heater: resistive, home-made

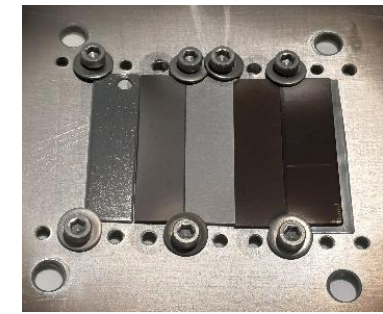
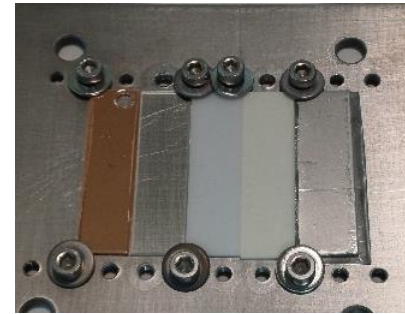


### Coating parameters:

- Gas: Kr
- $T_s$ : 500 ... 750°C
- $P$ :  $7 \cdot 10^{-4}$  ...  $5 \cdot 10^{-2}$  mbar
- PP: 35 ... 100 V
- Post anneal: 0 ... 72 hrs



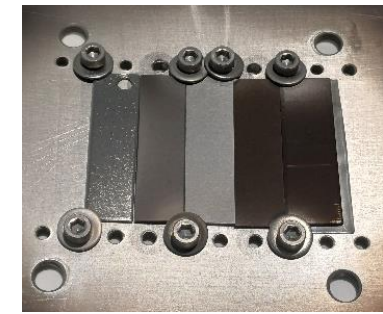
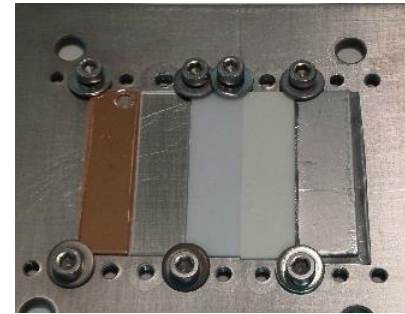
# Feasibility - $T_c$



Can we elaborate high quality  $Nb_3Sn$  films?

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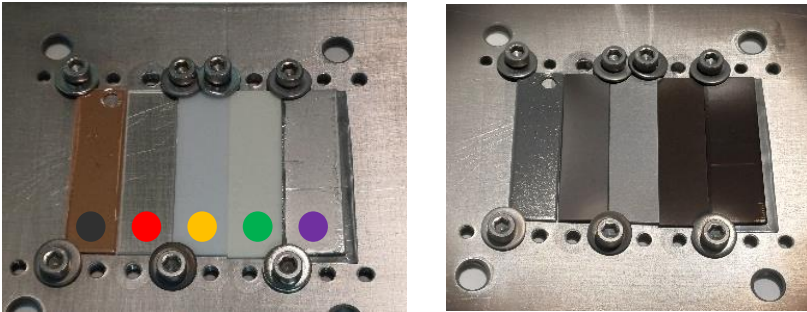
## DCMS

**Table 1.** Influence of the substrate on critical temperature of the Nb<sub>3</sub>Sn films.

Process pressure	Critical temperature (K)	
	Copper substrate	Ceramic substrate
$P = 1 \times 10^{-3}$ mbar	14.7 K	17.5 K
$P = 5 \times 10^{-2}$ mbar	15.5 K	17.4 K

<https://doi.org/10.1088/1361-6668/aaf61f>

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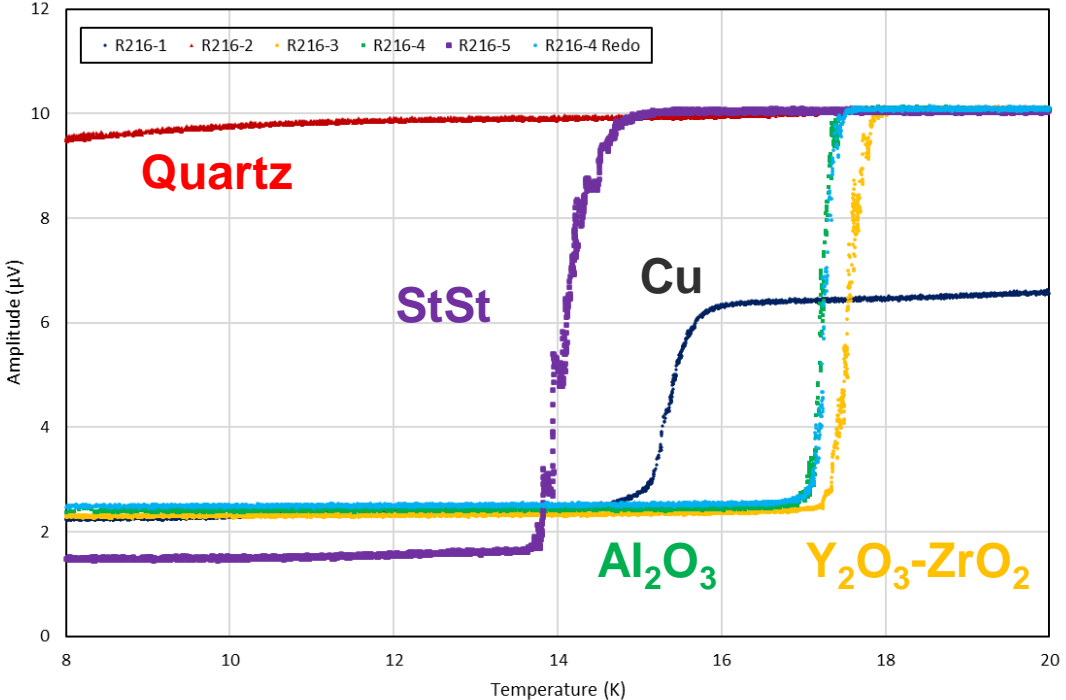
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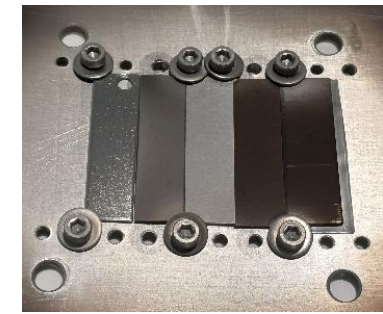
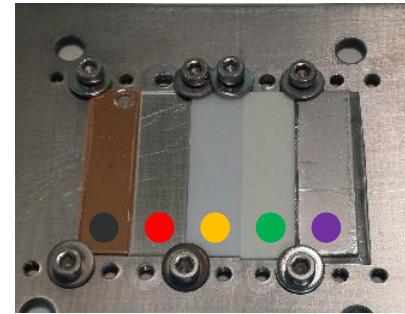
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## HiPIMS



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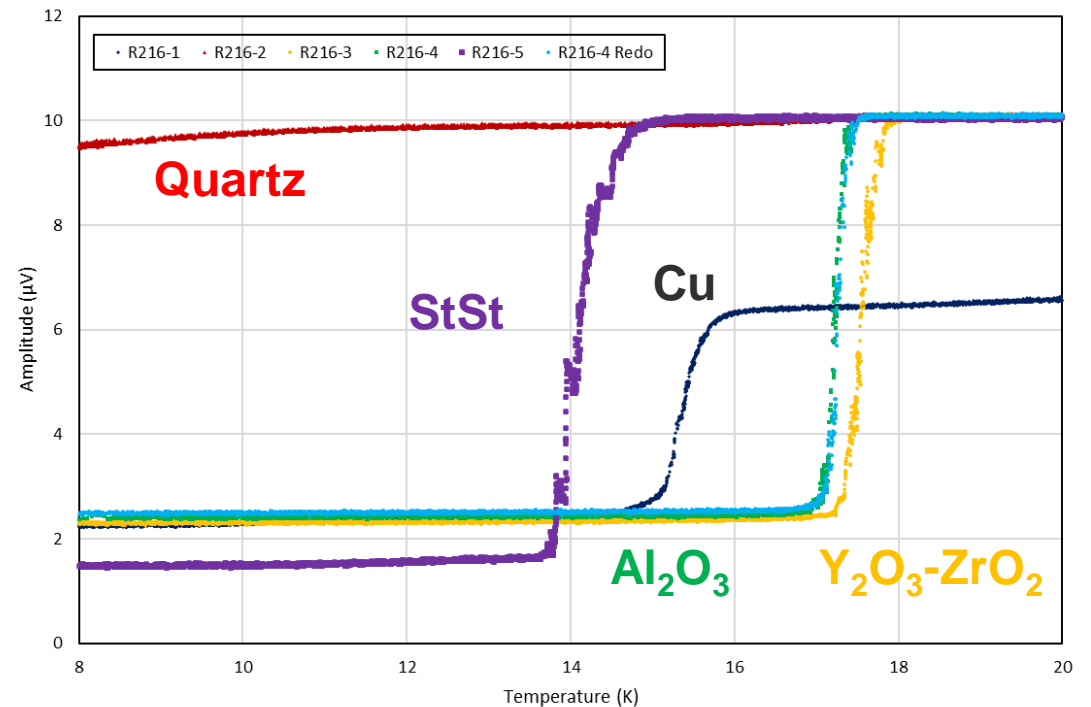
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**SUBSTRATE'S THERMAL EXPANSION COEFFICIENT DRIVES THE RESIDUAL STRESS  $\rightarrow$  LRO  $\rightarrow T_c$**

## HiPIMS

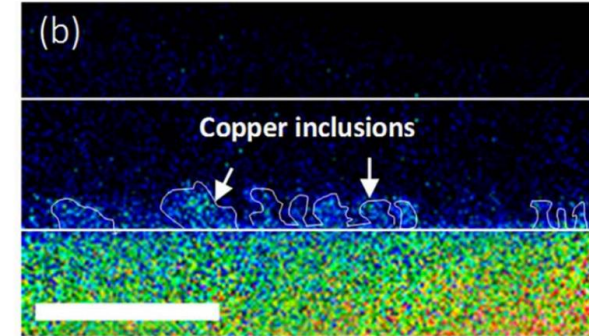
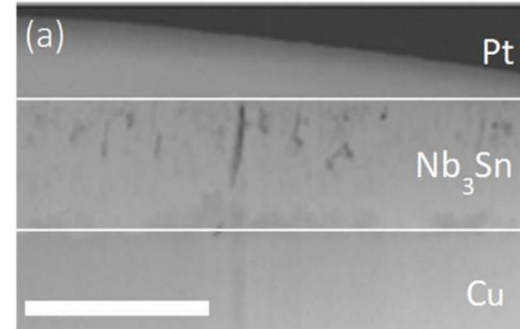




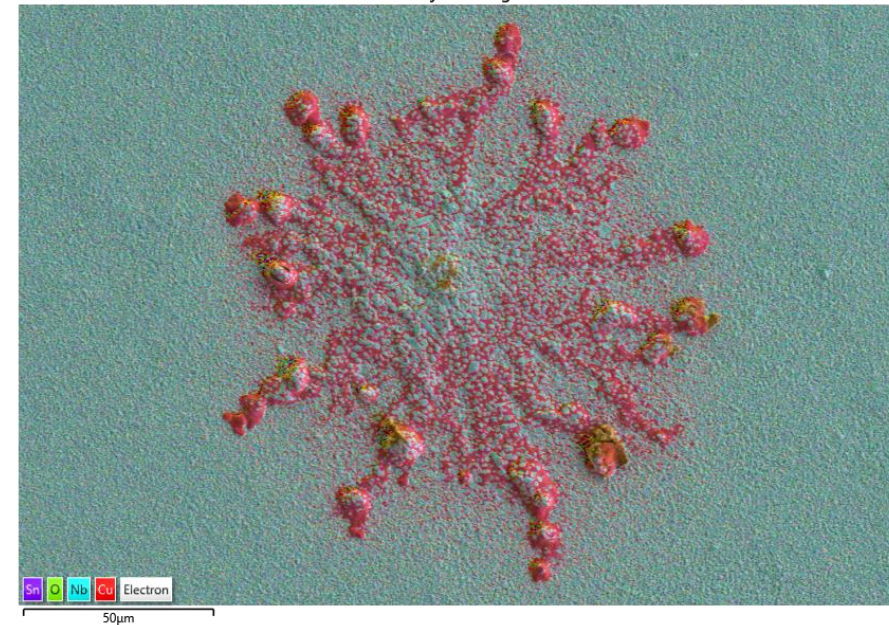
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## How problematic is Cu?

Interdiffusion → NC spots at the RF surface  
Also promoting the A15 phase formation



EDS Layered Image 1



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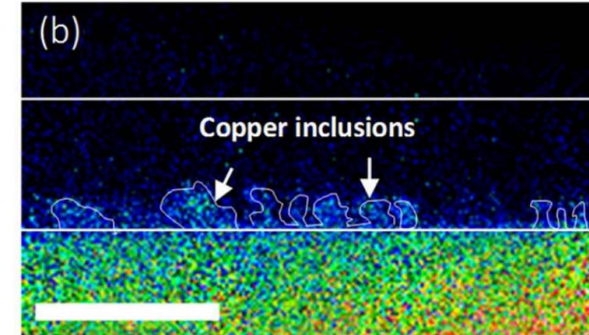
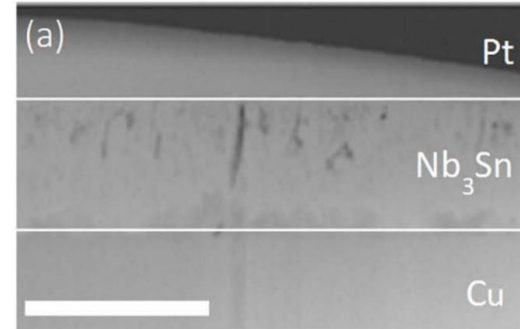
Interdiffusion → NC spots at the RF surface  
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## How to block it?

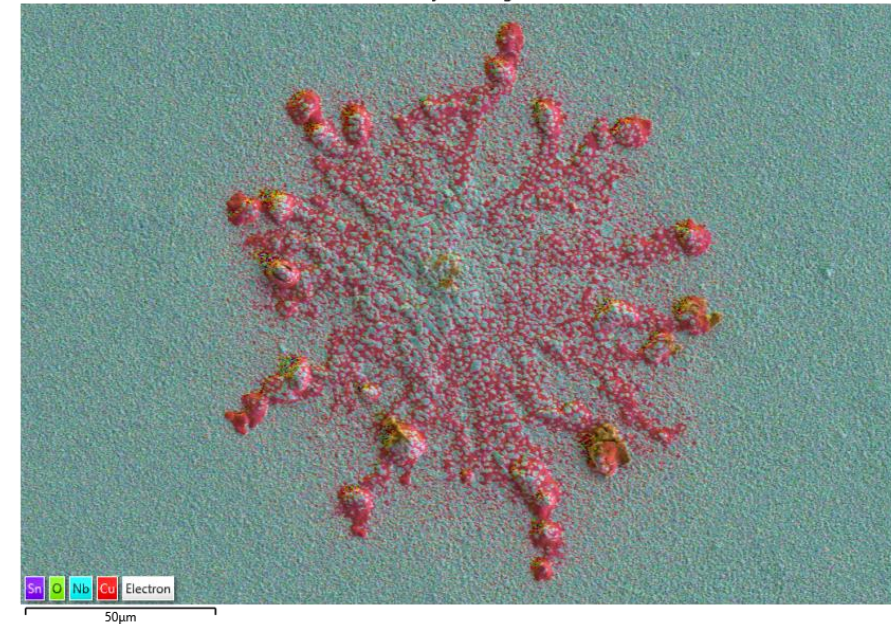
Diffusion barrier layer (Ta, HEA ... )

Ta: requires a very specific crystalline phase ( $\alpha$ )

HEA: promising, needs more investigations,  
amorphous even at high T



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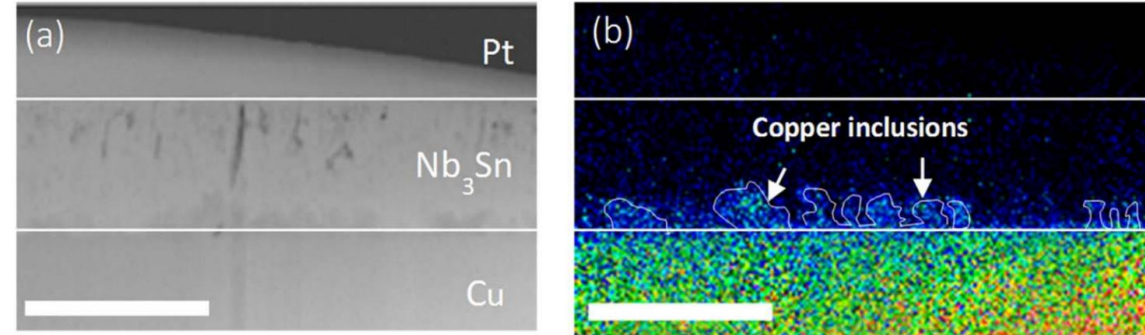
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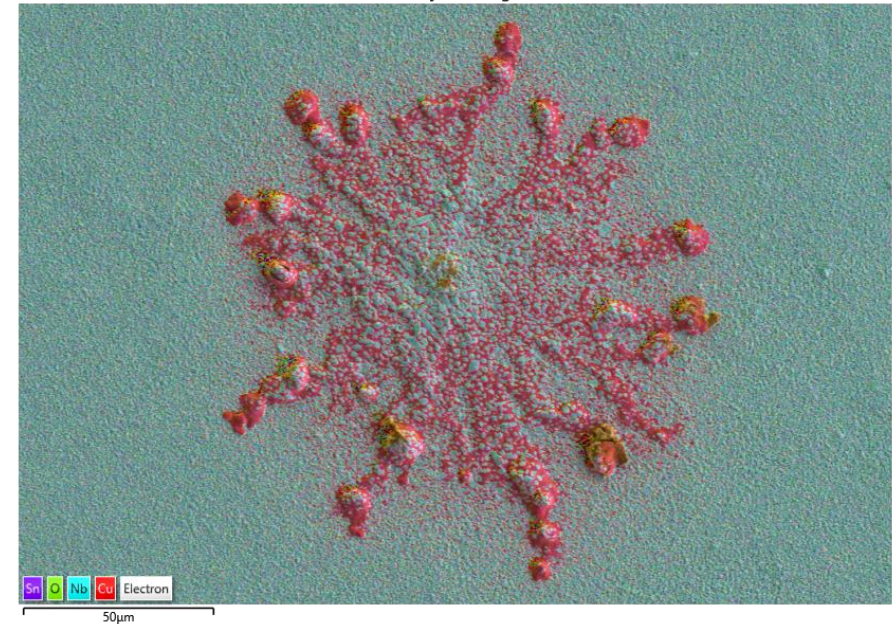
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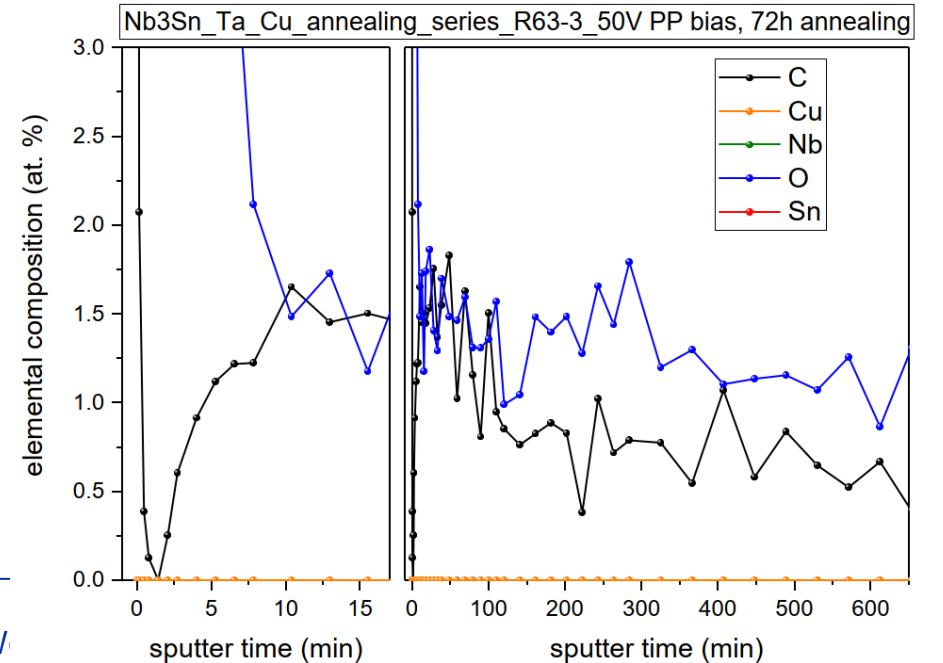
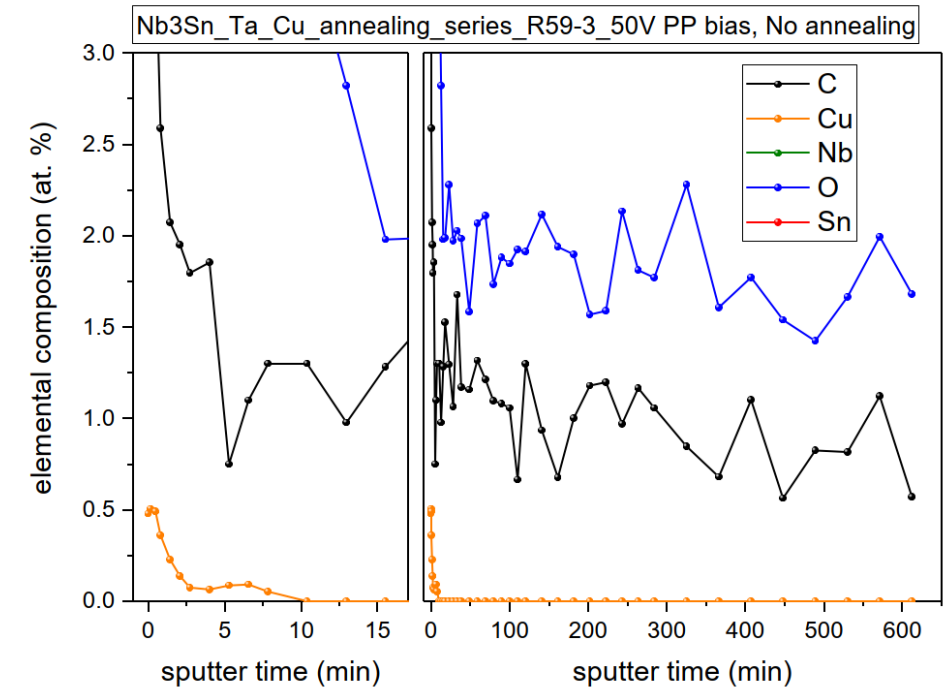
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HEA: promising, needs more investigations,  
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## Then... the surface is absolutely free of Cu?

**No**

Surface contamination.  
Disappears after HT.



# Feasibility – Cu

## Also observed:

A careful setup cleaning reduces surface Cu contamination.

Surface diffusion from samples

A problematic already known with dramatic industrial consequences

## For future applications and scale-up

How to manage this contamination?

**Curative approach:** post coating Cu wet etching : Ammonium persulfate

Cu at. %	Pre Rinse	Post Rinse
Sample 1	3.9	0.6
Sample 2	5.3	1.6

# Target management

## CERN's choice:

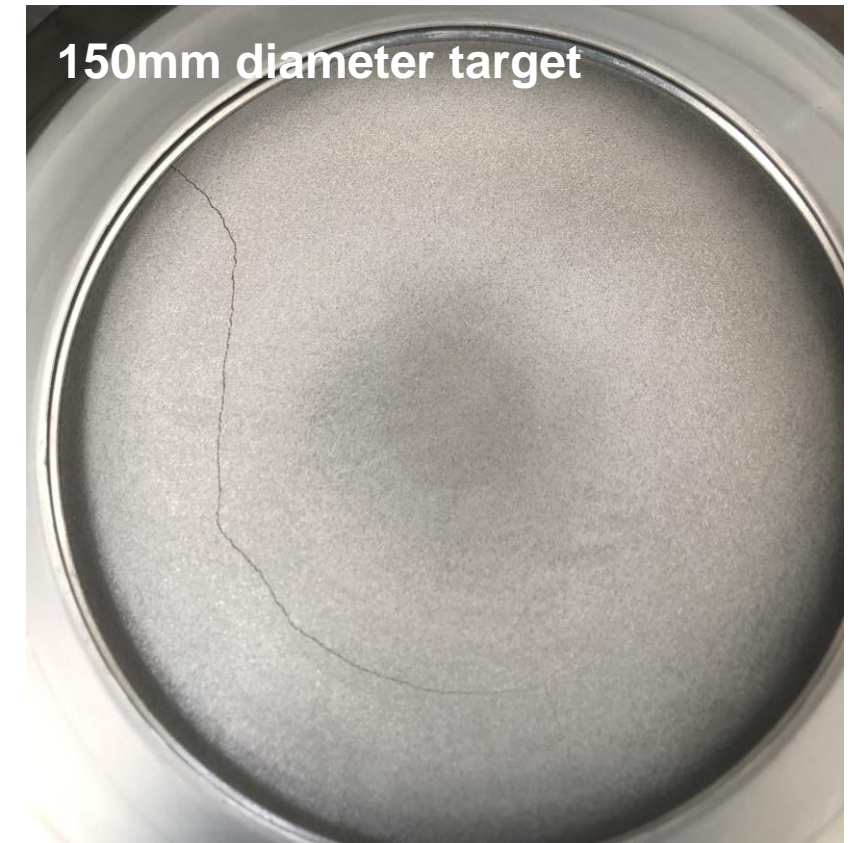
alloyed target : reduce the needs down to 2 targets: 1 for DBL and 1 for Nb<sub>3</sub>Sn

## Problematic:

- Fragile
- Prompt to cracking
- Dust creation
- Impossibility to buy cylindrically shaped targets

## Study on going to adress this specific issue:

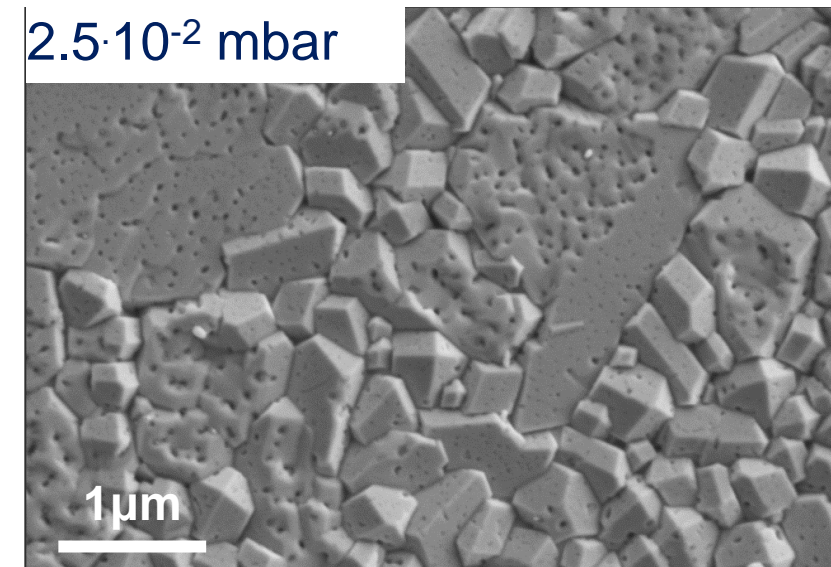
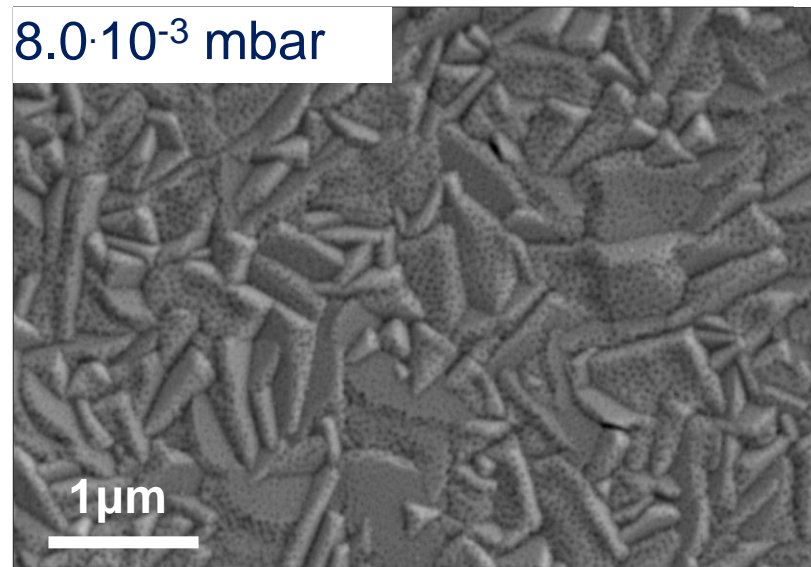
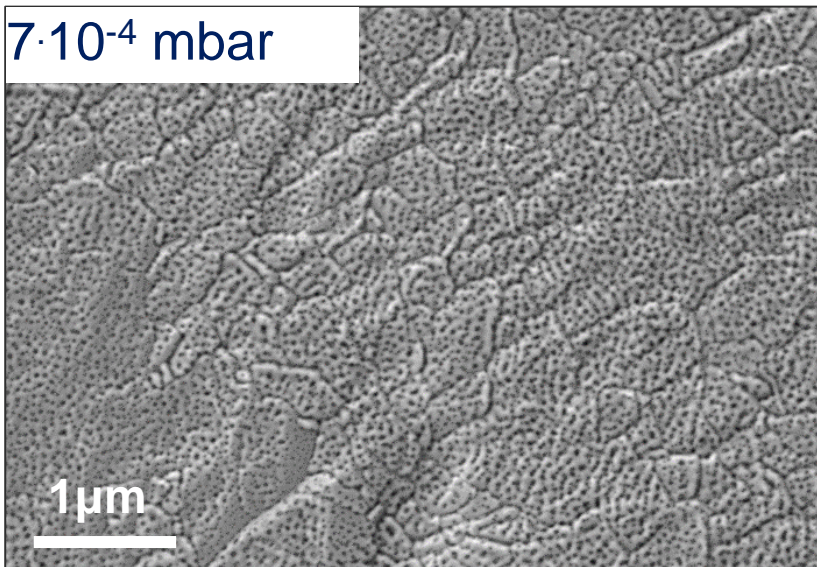
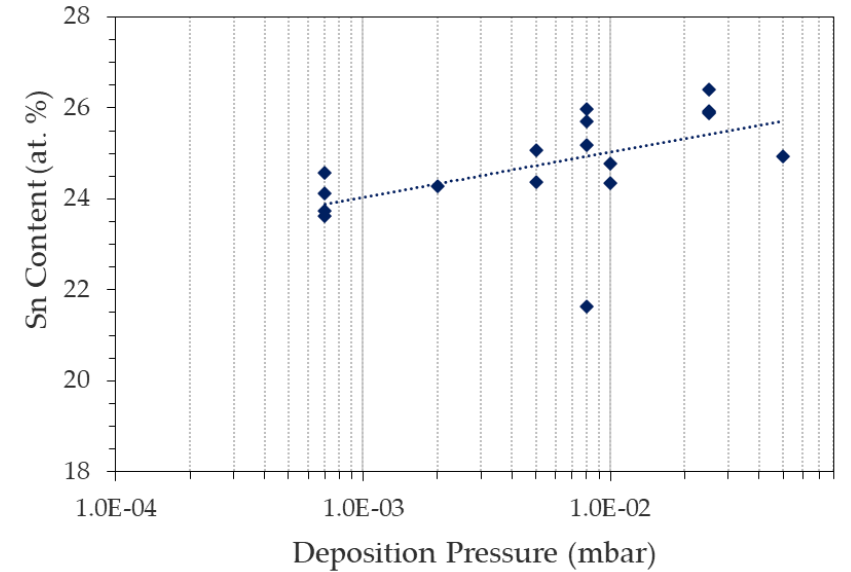
- Thermal cycles
- Power ramp-rate
- Max power
- Backing plate bonding strategy



# Some process parameters' effects

## Coating pressure:

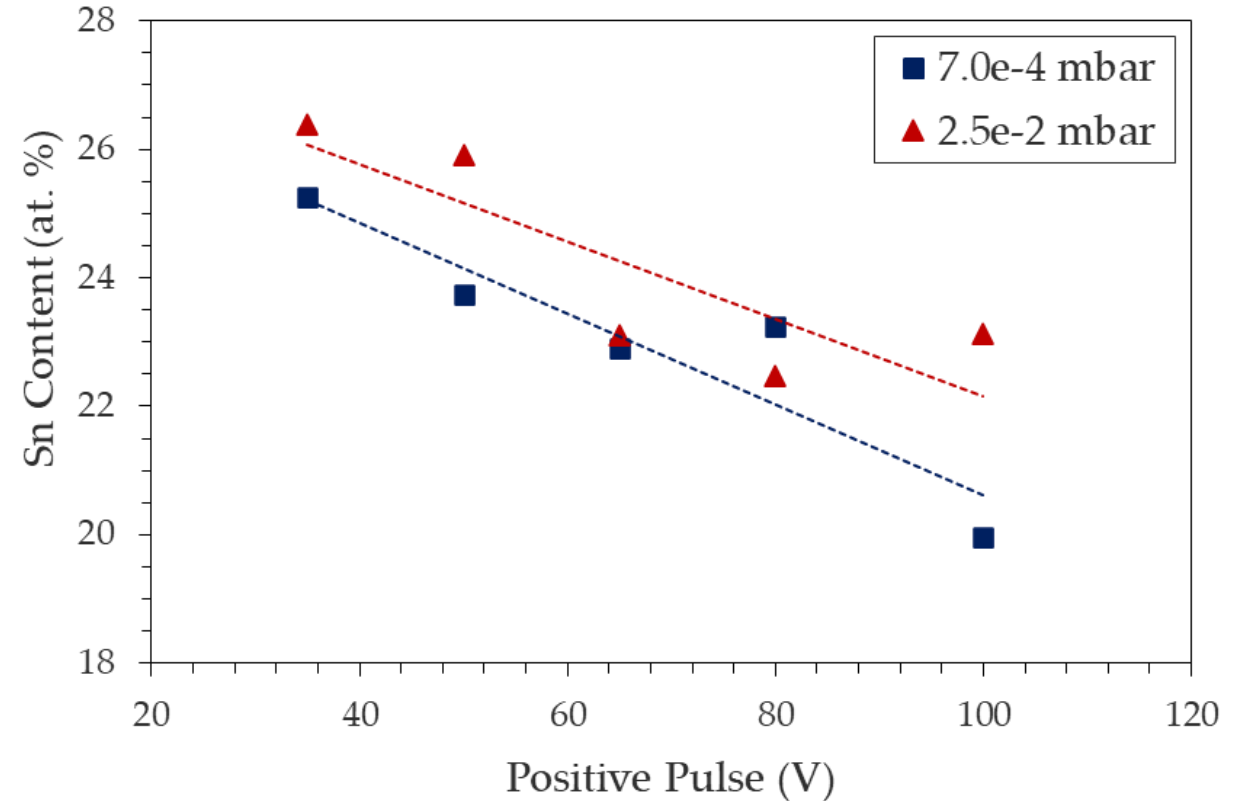
- Smoother at lower pressure (less gas phase collisions)
- Composition: Sn content increases with P
- An optimal has to be found between composition and roughness
- Films look as well more crystalline at high P (XRD quantitative analysis to be performed)



# Some process parameters' effects

## Positive Pulse:

- Sn very sensitive to re-sputtering
- Sn content decreases with positive pulse voltage
- Composition and density evolve on an opposite trend

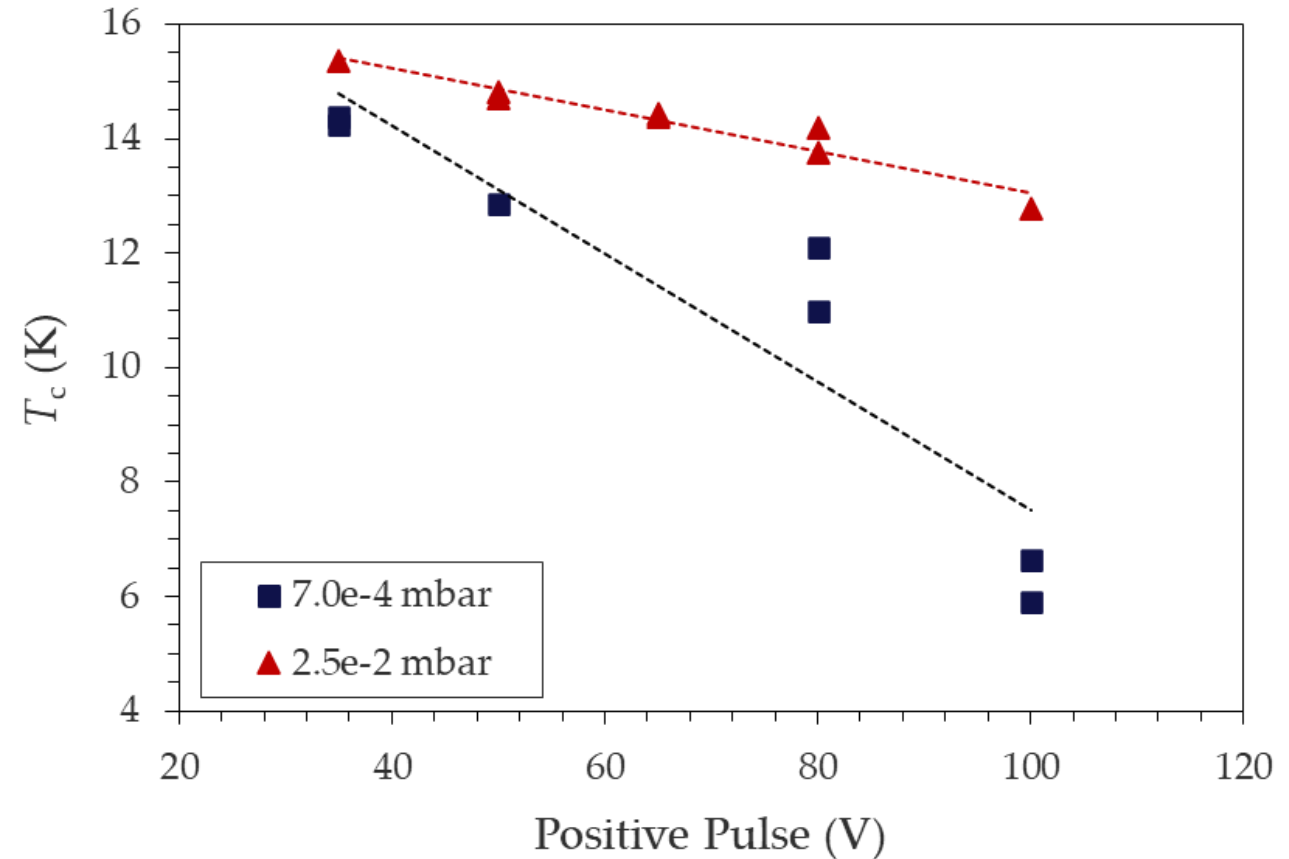




# Some process parameters' effects

## Effect on the $T_c$

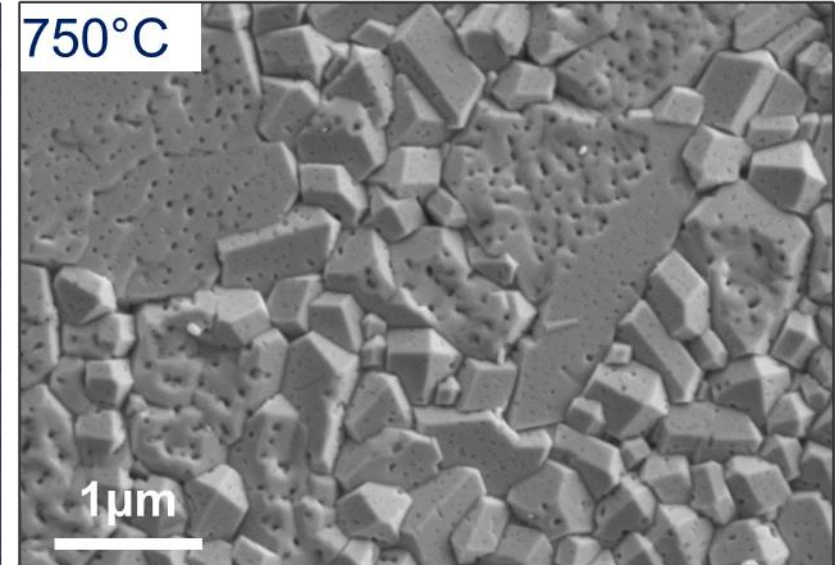
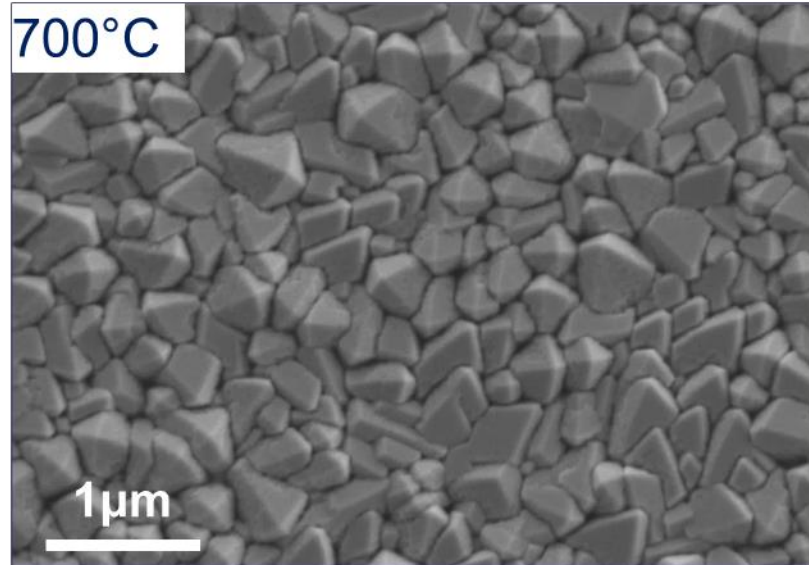
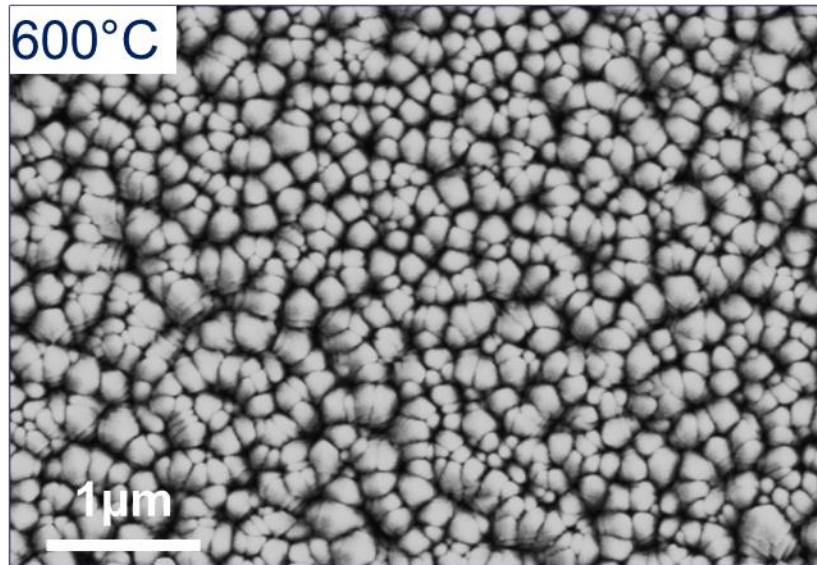
- Increase in pressure  $\rightarrow$  increase in Sn content  $\rightarrow$  increase in  $T_c$
- Increase in PP  $\rightarrow$  decrease in Sn content  $\rightarrow$  decrease in  $T_c$



# Some process parameters' effects

## Coating temperature

- For a given coating recipe
- Lower temperature → lower adatoms mobility
  - Porous layer
  - Layer appears much less crystalline



# Macroscopic defects library

**Problematic:** very time consuming to perform defect analysis (FIB-SEM, cross sections, TEM ...)

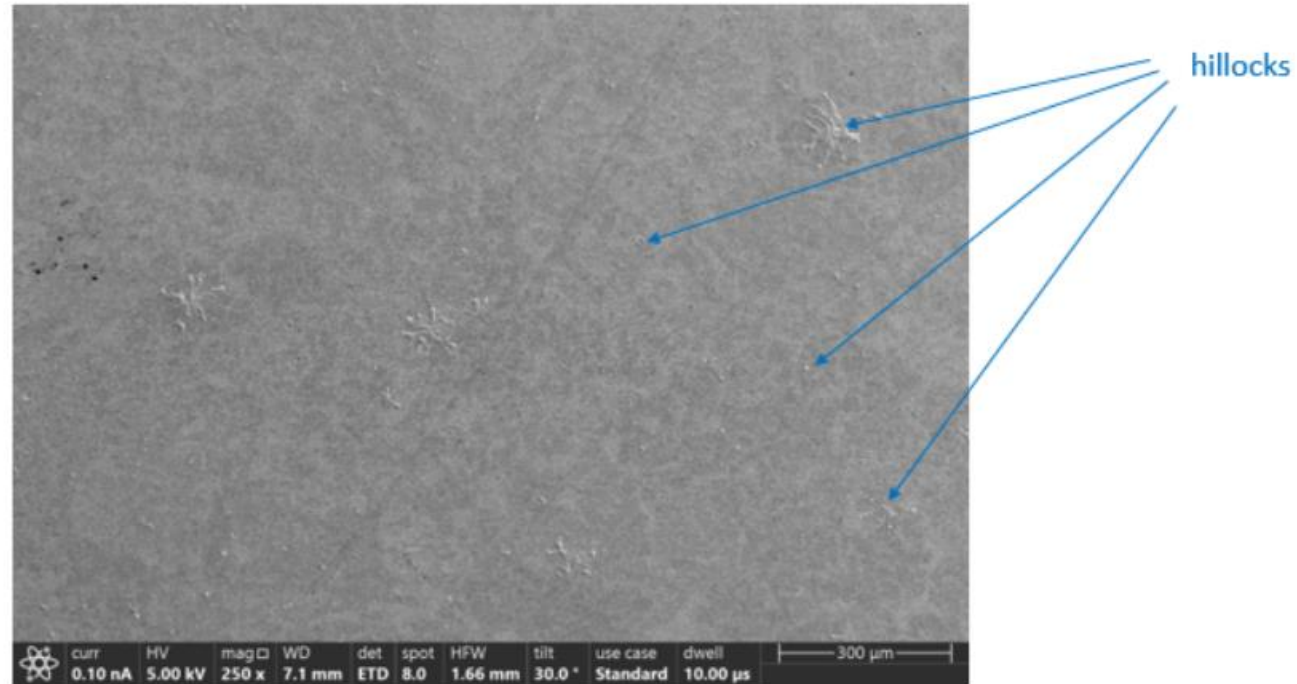
Solution: Establish a catalogue of visual defects that can be linked to microscopic feature in view of speeding process qualification → avoid unnecessary investigations



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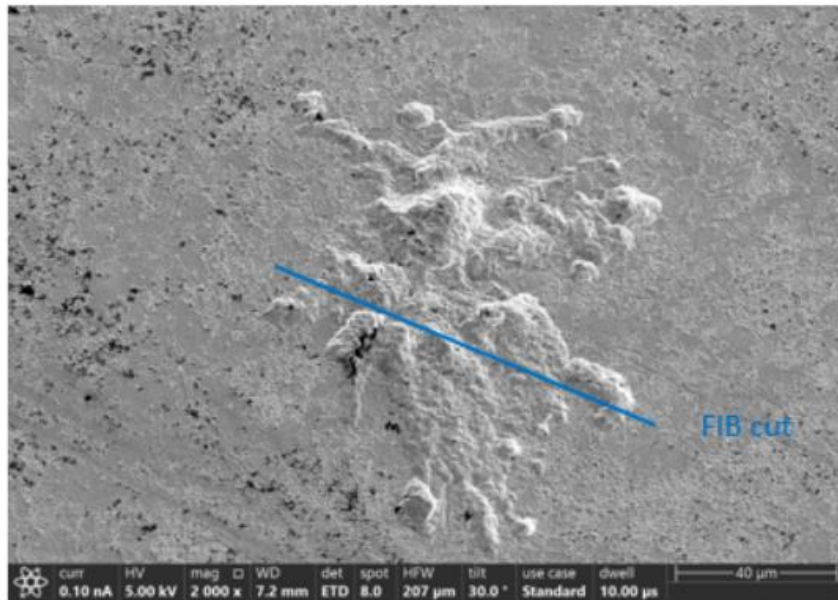


SEM image: surface with defects

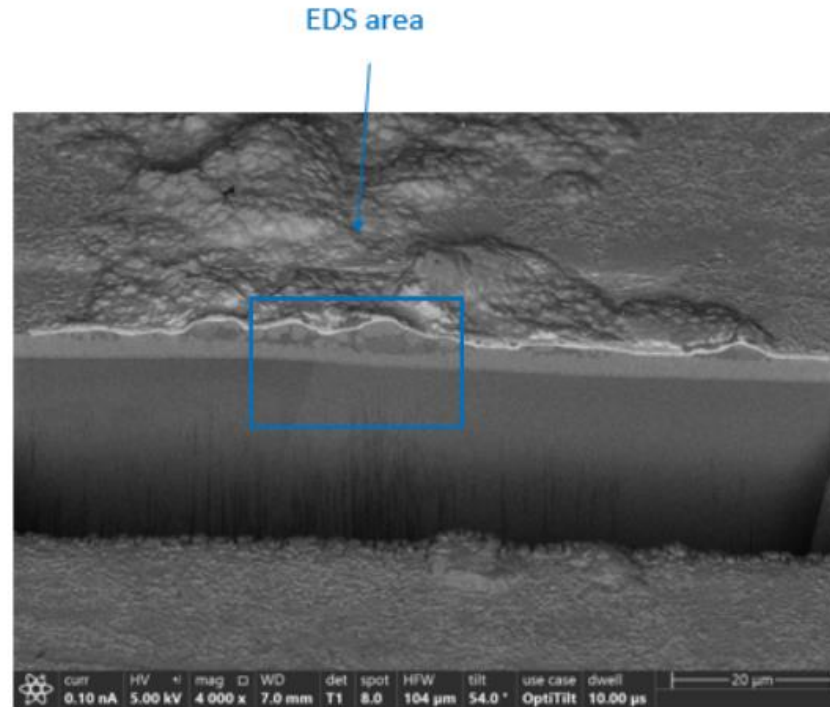
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SEM image: hillock



SEM image: FIB x-section through the hillock

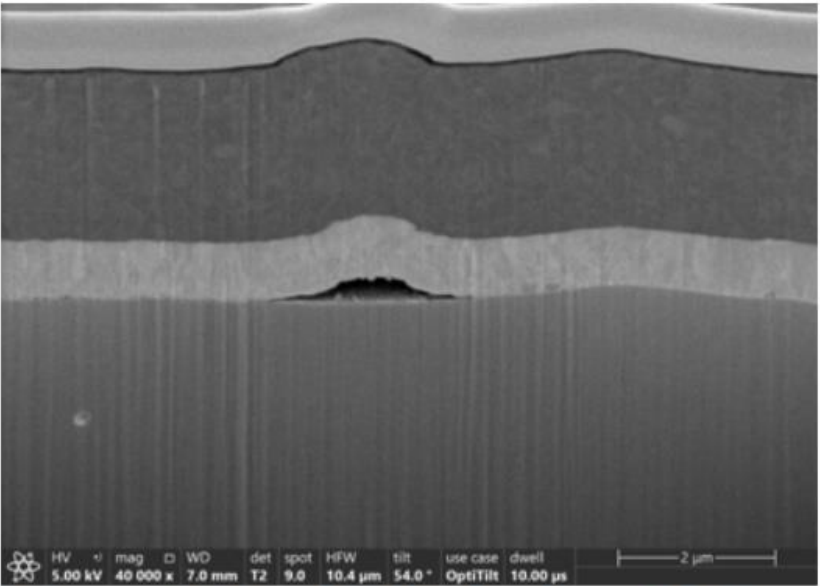
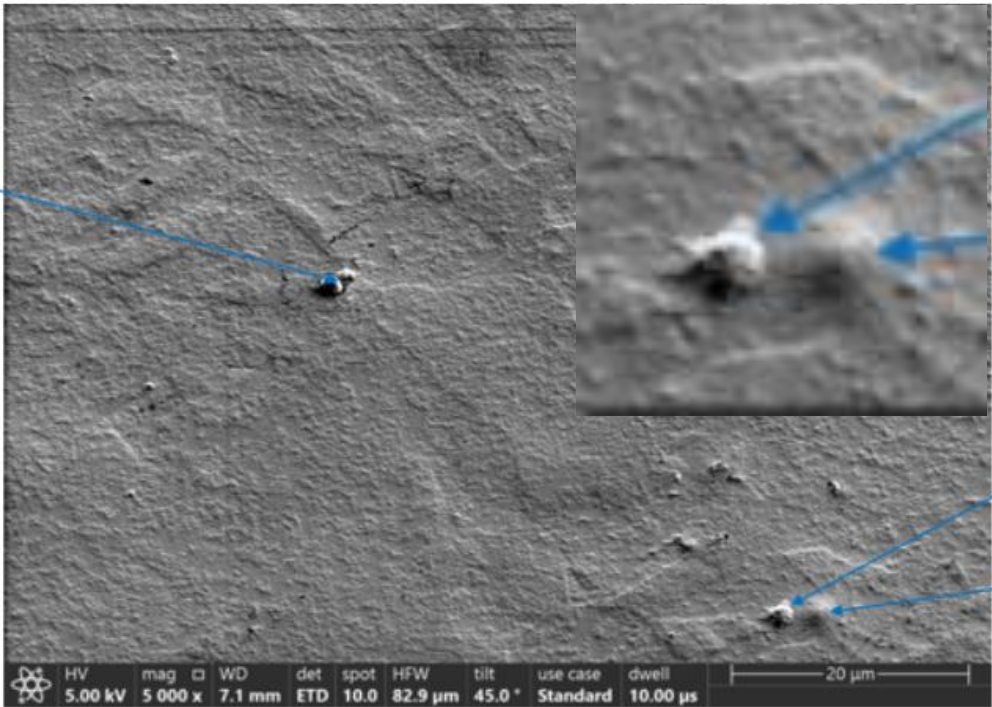
DBL failure

- Stress induced crack
- dust

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FIB cross section through the hillock and tapered hillock

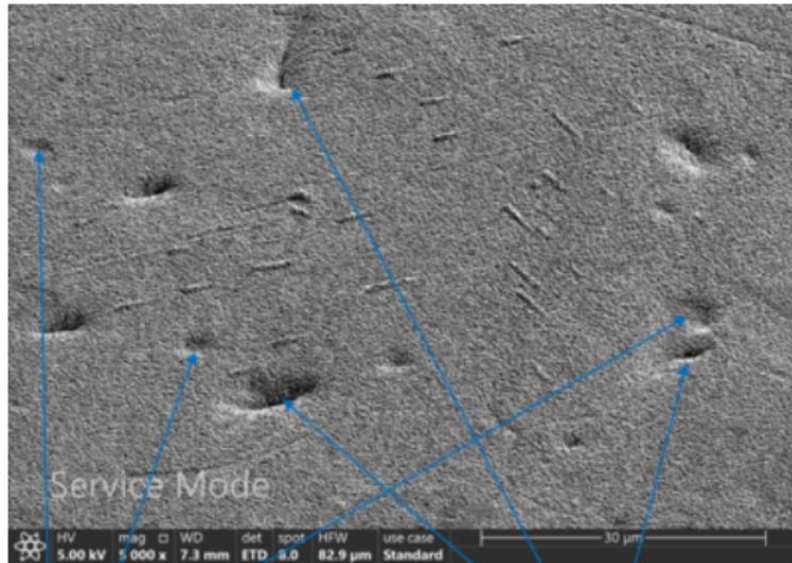
Surface particulate contamination  
Stress accumulation



# Macroscopic defects library

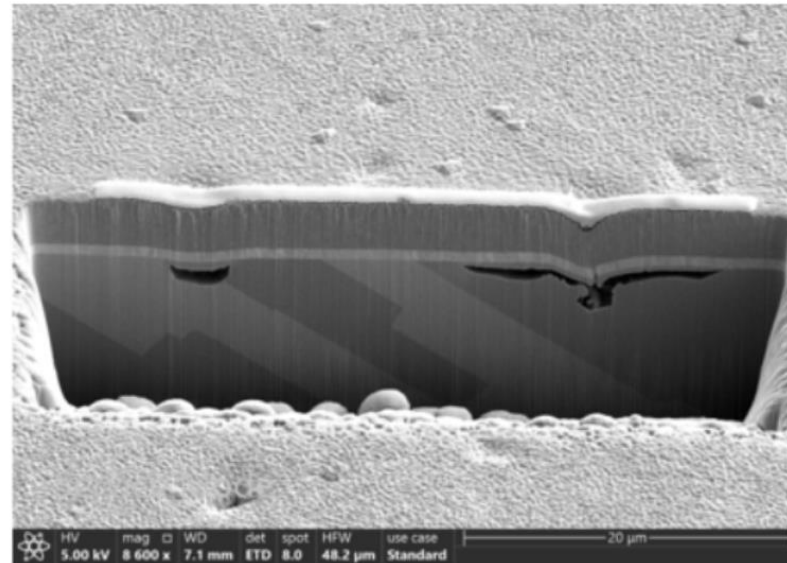
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hollows

hollows with crack



Cross-section through a hollow and hollow with crack

Hollows and hollows with crack are associated with voids or maybe blowholes in the Cu substrate.

Cu diffusion.  
Already seen in HIE-ISOLDE

Typical of high temperature processes

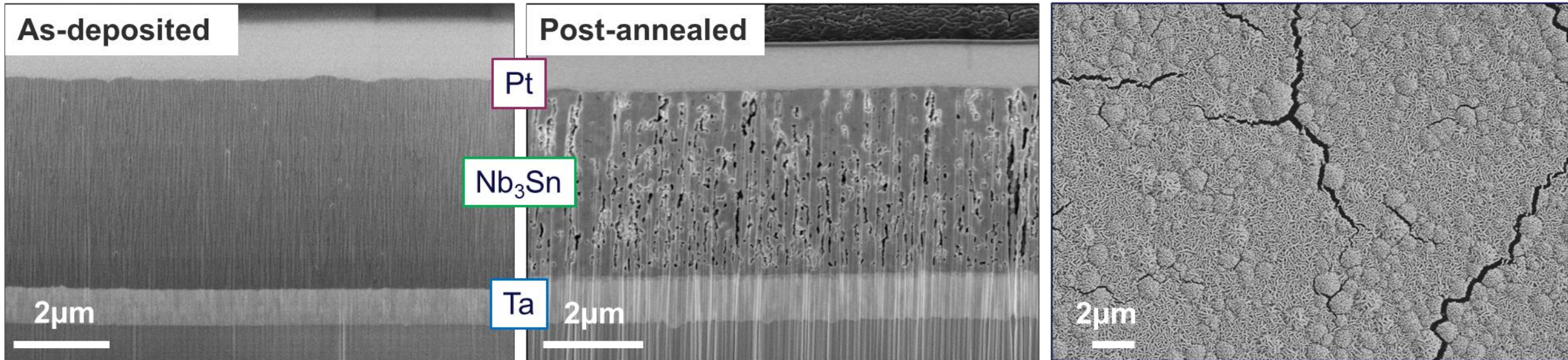
→ Layer fragility?

# Side Note

Coating at low T and reacted after coating

**SYSTEMATICALLY LEADS TO FILM CRACKING**

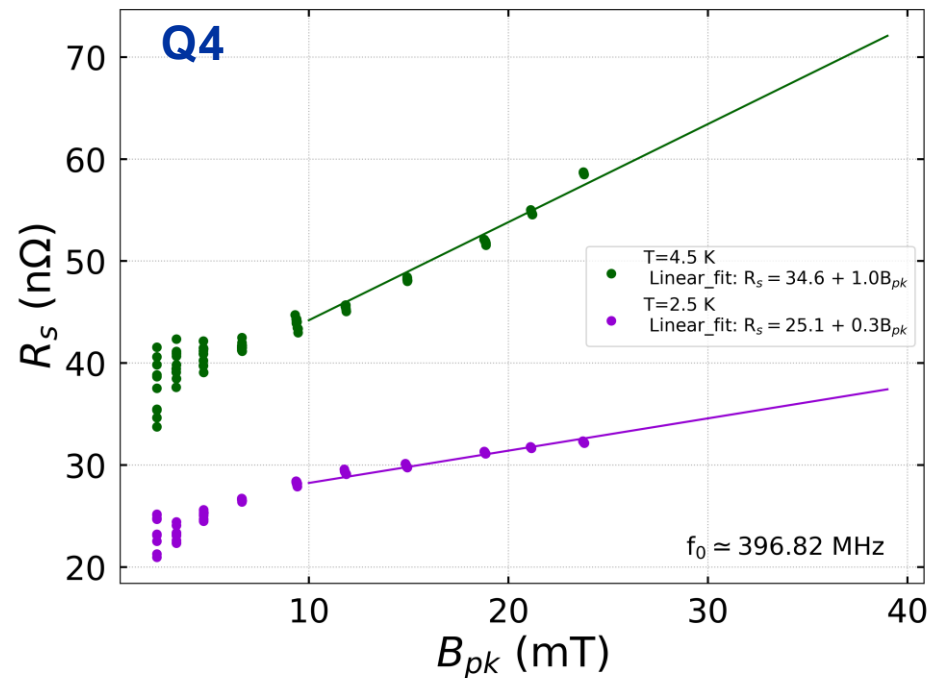
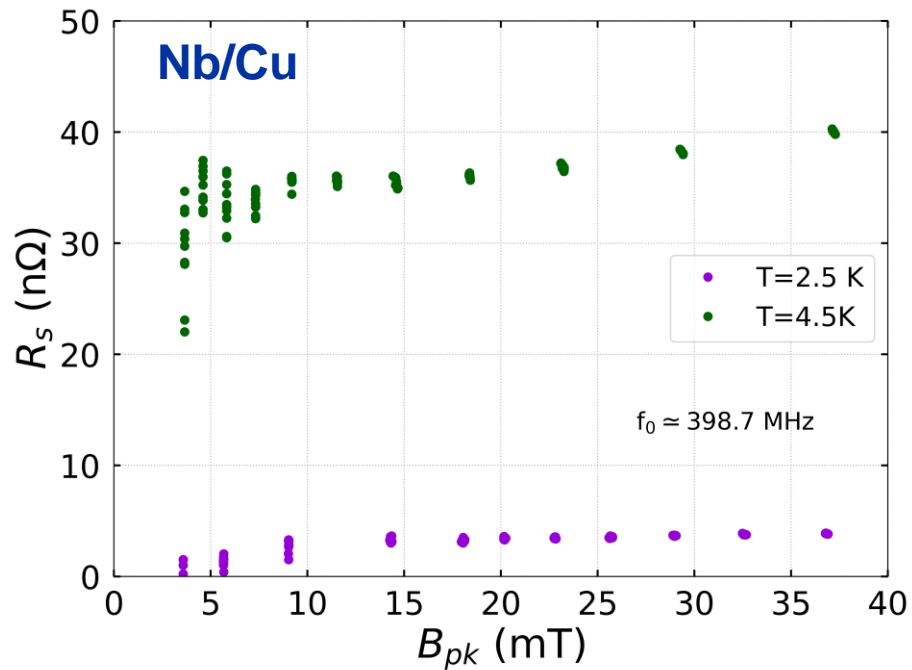
This option is for the moment put aside as a potential process route



# QPR samples tests – RF data

**Technical remark:** heating up a QPR to a suitable temperature is an actual challenge.

Right now: only home-made heater has shown satisfactory behavior.

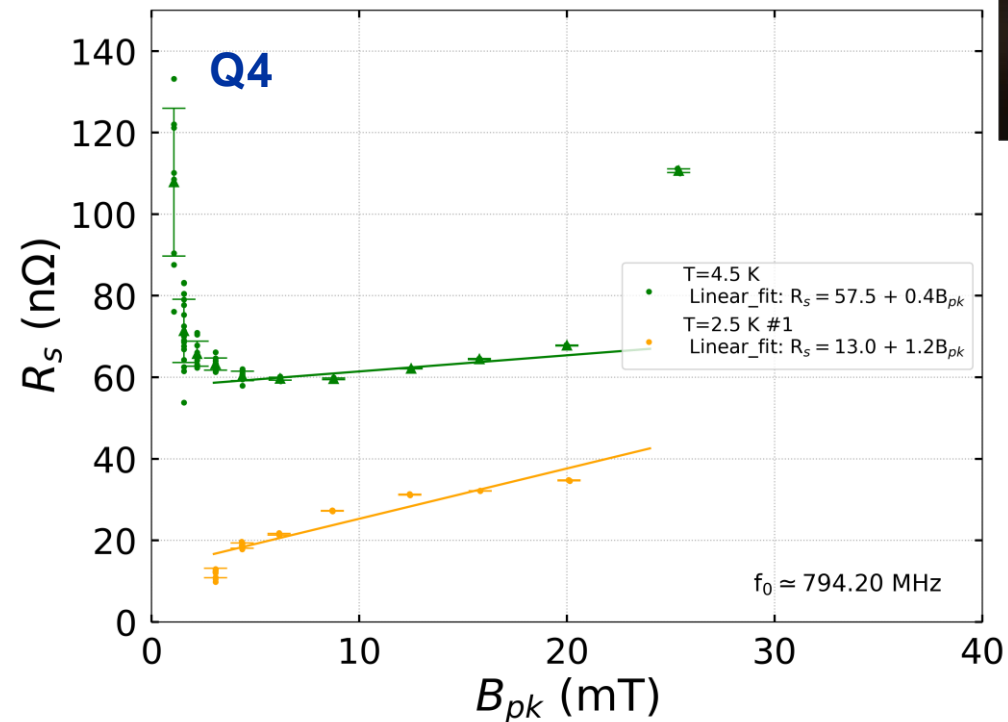
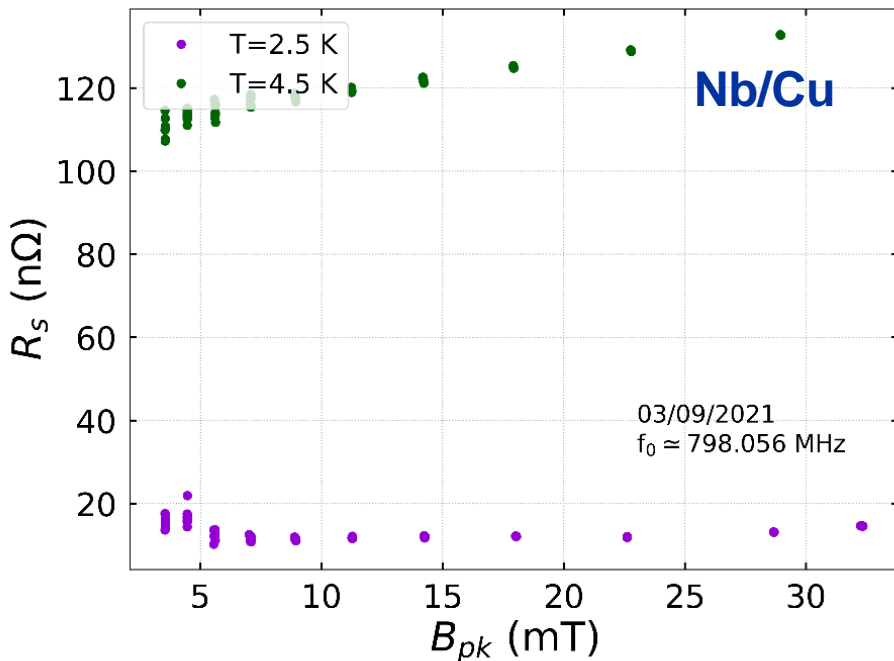




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# RADES– RF data

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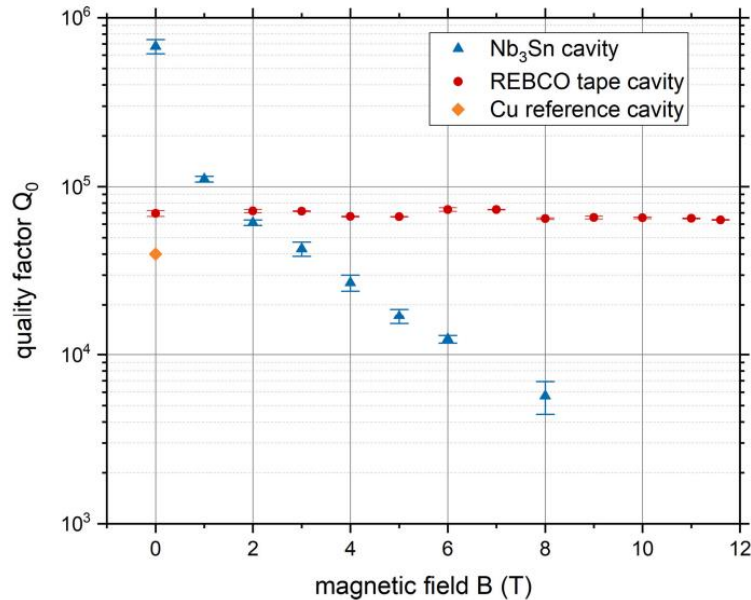


Fig. 6. Results of quality factor measurements with the cavity immersed in liquid helium. The resonance frequency of the cavities is  $f = (8.8 \pm 0.1)$  GHz at 4.5 K.

J. Golm *et al.*, "Thin Film (High Temperature) Superconducting Radiofrequency Cavities for the Search of Axion Dark Matter," in *IEEE Transactions on Applied Superconductivity*, vol. 32, no.

4, pp. 1-5, June 2022, Art no. 1500605, doi: 10.1109/TASC.2022.3147741.



(a)



(b)

Fig. 3. Photographs of the (a) coating setup and (b) a cavity half in coating position.

TABLE I  
COATING PARAMETERS FOR THE Ta AND Nb<sub>3</sub>Sn LAYERS

	<b>t</b> (min)	<b>p</b> (mbar)	<b>Pw</b> (W)	<b>T</b> (°C)	<b>Main pulse</b>		<b>Positive Pulse</b>	
					t ( $\mu$ s)	$\nu$ (kHz)	t ( $\mu$ s)	$\Delta t$ ( $\mu$ s)
<b>Ta</b>	40	$1 \times 10^{-3}$	350	750	50	1	200	4
<b>Nb<sub>3</sub>Sn</b>	75	$7 \times 10^{-4}$	350	750	-	-	-	-



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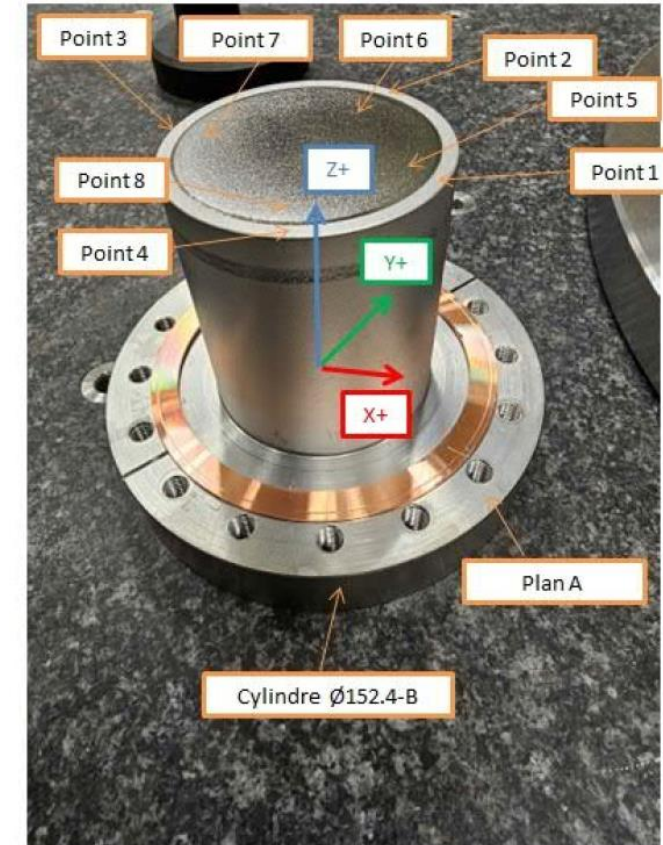
## BE CAREFUL:

High temperature during coating can lead to the mechanical deformation of the QPR surface → bulging

Serious impact onto the RF surface resistance estimation

Full surface metrology is **MANDATORY** after RF test to feedback the actual profile to RF simulation.

Depending on how you mount the sample: surface can either collapse, bulge or even the Nb tube could buckle (horizontal position)

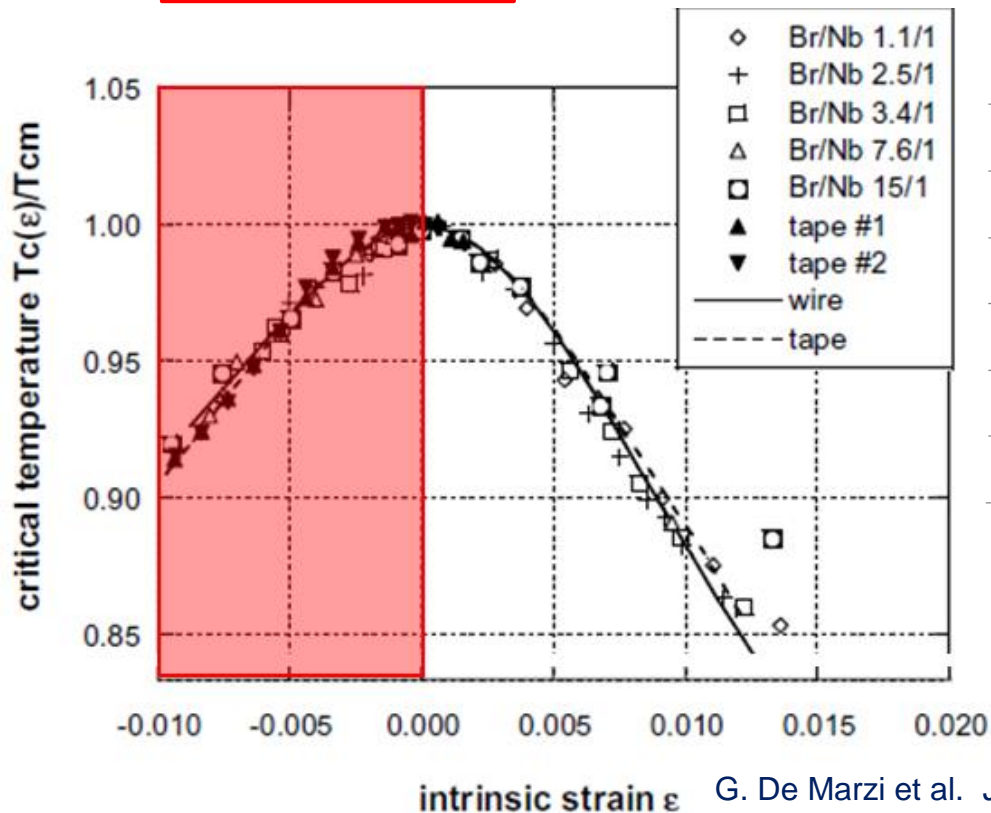


Regular surface re-machining might be a standard to apply

# QPR samples tests – Material analysis

## Residual stress quantification by XRD analysis

Compressive residual stress



### Residual stress by XRD (MPa)

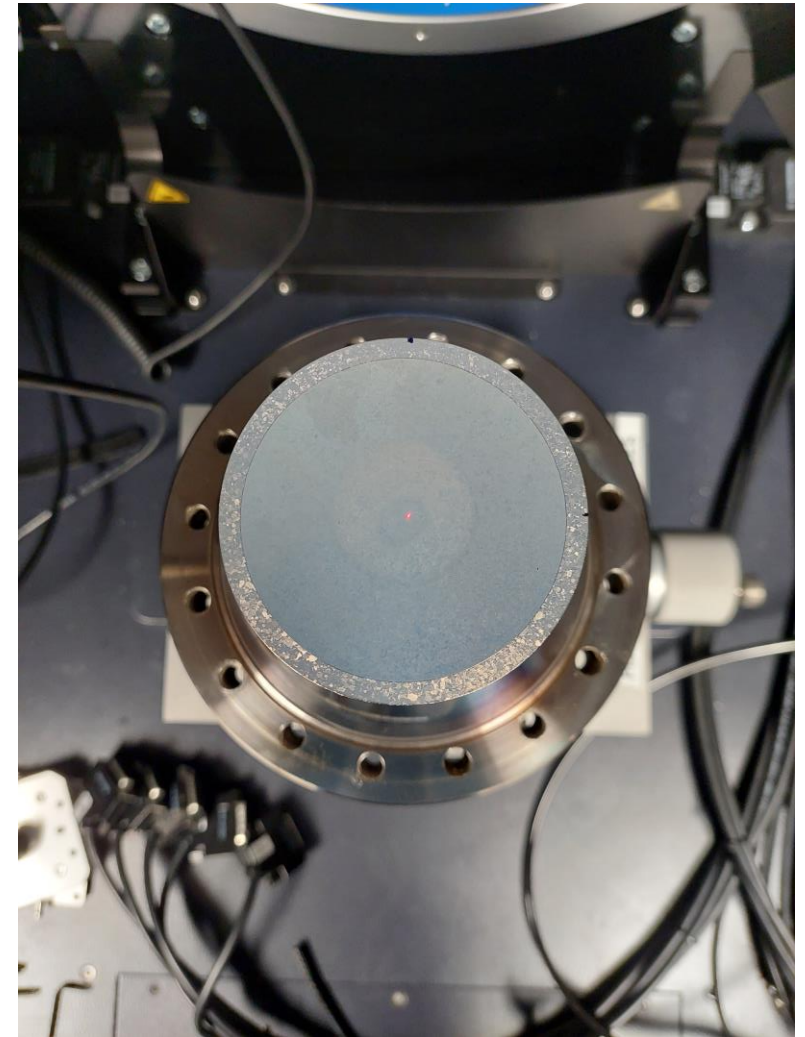
Centre #1:  $-888 \pm 20$

Centre #2:  $-760 \pm 20$

Outer #1:  $-975 \pm 19$

Outer #2:  $-949 \pm 13$

Outer #3:  $-1236 \pm 17$



# Scale-up strategy at CERN

1. **One have to confirm the competitiveness of Nb<sub>3</sub>Sn/Cu wrt Nb/Cu**
2. **Continue with QPR testing and process optimization**
3. **Objects to be coated: last SRF CERN workshop consensus on moving on straight to 800MHz cavities. (potentialy compatible with 1.3GHz)**
4. **The cost of such a coating hardware will be > 500kCHF : one should target for success**
5. **Sub-components (target) shall be comissioned and validate prior full integration**
6. **New CERN SRF building to be «furnished» in 2029**

# Outlook

- **Nb<sub>3</sub>Sn/Cu is an attractive system to compete with Nb/Cu**
- **800MHz performance appear promising**
- **Linear thermal dilatation coefficient difference between substrate and film remains an issue : look for another substrate?**
- **Cu interdiffusion can be controlled/mitigated. Does not appear yet as a showstopper.**
- **High temperature is a pre-requisite DURING coating**
- **Target fragility has to be handled for a proper scale-up: could be a showtopper**
- **RF tests on QPR are showing performance close to Nb/Cu: there is room for hope**